



NANOTECH FRANCE 2026 / GAMS 2026 / NANOMATEN 2026

Joint International Conferences and Exhibition

17 - 19 June 2026

Paris – France

Book of Abstracts

Organizer



SETCOR
Conferences & Exhibitions

June 17, 2026		
09:00 - 12:00	Onsite Participant registration	
09:00 - 10:00	Morning Coffee Break	
Nanotech France / NanoMatEn / GAMS 2026 Joint Plenary session		
Amphithéâtre		
Session's Chairs: Prof. Jacques Jupille, Univ. Pierre et Marie Curie (UPMC), CNRS Paris, France Prof. Andrea Lamberti, Politecnico di Torino, Italy		
10:00 - 10:30	Graphene-based Nanocomposites for Application in Microsupercapacitor: (Electro)Synthesis and Characterisations C. Debiemme-Chouvy	Prof. Catherine Debiemme-Chouvy, Sorbonne University, France
10:30 - 11:00	Hypotaxy of Wafer-scale Single Crystal Transition Metal Dichalcogenides G-H. Lee	Prof. Gwan-Hyoung Lee, Seoul National University, Rep. Korea
11:00 - 11:30	Atomic scale characterisation of microstructure and composition engineered high performance thermoelectric materials A. Genç	Prof. Aziz Genç, Universitat Autònoma de Barcelona, Spain
11:30 - 12:00	Route to international standardisation of advanced nanomaterials via pre-normative interlaboratory studies C. Clifford	Dr. Charles Clifford, National Physical Laboratory, UK
12:00 - 14:00 Lunch Break		
NanoMeasureFrance Association / SMURFnano Joint workshop: Metrology and Industrial Advanced (Nano)Materials: Collaborative Approaches to Method Development, Assessment, and Global Standardization		
Amphithéâtre		
Session's Chairs: Dr. François-Xavier Ouf, Laboratoire National de métrologie et d'Essais (LNE), France Dr. Ute Resch-Genger, Federal Institute for Materials Research and Testing (BAM), Germany		
14:00 - 14:30	Advanced Materials from a (pre-) regulatory perspective: Status Quo and Challenges A. Haase	Dr. Andrea Haase, German Federal Institute for Risk Assessment (BfR), Germany
14:30 - 14:50	Advanced Materials (AdMa) – Nano and Beyond Impulses from the Perspectives of VCI, Standardization, and SMURFnano G. Lindner	Dr. Gottlieb Lindner, Evonik Operations GmbH, Germany
14:50 - 15:10	NanoMeasureFrance: a public-private initiative to build common characterization solution F-X. Ouf	Dr. François-Xavier Ouf, Laboratoire National de métrologie et d'Essais (LNE), France
15:10 - 15:30	Metrological challenges for surface functionalities analysis I. Tavernaro, A. Matiushkina, L. Scholtz, M. Richter, C. Homann, J. Radnik and U. Resch-Genger	Dr. Ute Resch-Genger, Federal Institute for Materials Research and Testing (BAM), Germany
15:30 - 15:50	Reliable workflows for the elemental analysis of Graphene-Related 2D Materials with SEM/EDS and XPS P. Mrkwitschka, V.-D. Hodoroba and J. Radnik	Dr. Jörg Radnik, Federal Institute for Materials Research and Testing (BAM), Germany
16:00 - 16:30 Afternoon Coffee Break		

16:30 - 17:00	Towards a metrological framework for nanotherapeutics: outcomes of the MetrNo project R. Schürmann , U. Resch-Genger, C. Gollwitzer, E. Alasonati, L. Mortati and A. Ceccaldi	Dr. Robin Schürmann , Physikalisch-Technische Bundesanstalt (PTB), Germany
17:00 - 17:20	The potential of asymmetrical flow field-flow fractionation platforms for the reliable quantification of metal-based active ingredients in nanomedicines D. Bartczak , G. Redondo-Fernandez, A. Sikora, Z. Varga and H. Goenaga-Infante	Dr. Dorota Bartczak , LGC-National Measurement Laboratory, UK
17:20 - 17:40	Surface chemistry in nanomedicine : The (simple) case of Super-SPIO20. G. Cotin and D. Felder-Flesch	Dr. Geoffrey Cotin , SUPERBRANCHE, France
17:40 - 18:00	From metrology to industry: Addressing challenges in nanomaterial characterization L. Crouzier	Dr. Loïc Crouzier , L'Oréal France, France
18:00 - 18:40	Q&A session and round table	